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In: Proceedings of the Hawaii International Conference on System Sciences, Vol. 1, 01.01.1998, p. 48-57. Research output : Contribution to journal > Conference article > peer-review Dennis, AR , Valacich, JS , Speier, C & Morris, MG 1998. ' Beyond media richness: An empirical test of media synchronicity theory ', Proceedings of the Hawaii International Conference on System Sciences , vol ...

Beyond media richness: An empirical test of media ...
INTERNATIONAL TEST CONFERENCE 0-7803-5092-8/98 \$1 0.00 0 1998 IEEE . 2. Review of Target Circuit Families Generally speaking most logic circuits can be classified in the fol- lowing four broad categories: Combinational static circuits, DCVS circuits (static or dynamic), pass gate logic and dynamic domino

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